

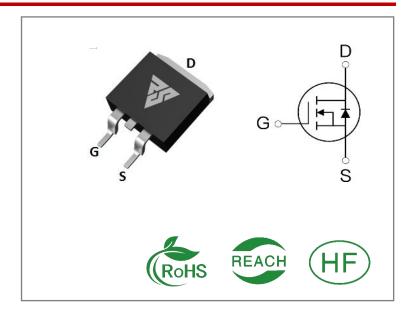
ID	R <sub>DS</sub> (ON)(Typ)	VDSS
18A	0.28Ω	500V

## **Applications:**

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

#### **Features:**

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



## **Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RS18N50S	T0-263	RS18N50S	Tape&reel	800 PCS

### Absolute Maximun Ratings Tc= 25°C unless otherwise specified

Symbol	Parameter	RS18N50S	Units
VDSS	Drain-to-Source Voltage	500	V
ID	Continuous Drain Current TC=25℃	18	Δ
IDM	Pulsed Drain Current (Note*1)	72	А
PD	Power Dissipation	140	W
VGS	Gate- to- Source Voltage	±30	V
EAS	Single Pulse Avalanche Engergy L = 10mH,,VDD = 50V, RG = 25Ω	600	mJ
	Maximum Temperature for Soldering		
TL TPKG	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	300 260	°C
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

<sup>\*</sup> Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.



#### **Thermal Resistance**

Symbol	Parameter	RS18N50S	Units	Test Conditions
RθJC	Junction-to-Case	0.89	°C/W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}\mathrm{C}$
RθJA	Junction-to- Ambient	62.5		1 cubic foot chamber,free air.

## **OFF Characteristics** TJ= 25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BVDSS	Voltage				V	VGS=0V,ID=250μ A
IDSS	Drain- to- Source Leakage Current			1	μΑ	VDS=500V,VGS= 0V
IGSS	Gate- to- Source Forward Leakage			100	<b></b> Λ	VGS=30V ,VDS=0 V
1033	Gate- to- Source Reverse Leakage			-100	nA	VGS=-30V ,VDS= 0V

# ON Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On- Resistance(Note*2)		0.28	0.34	Ω	VGS=10V,ID=9A
VGS(TH	Gate Threshold Voltage	3		4	٧	VGS=VDS,ID=25 0μA

# Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time		50			
trise	Rise Time		36			VDS=250V
td(OFF)	Turn- OFF Delay Time		226		nS	ID=18A RG=25Ω
tfall	Fall Time		60			



**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Ciss	Input Capacitance		2350			VGS=0V
Coss	Output Capacitance		225		рF	VDS=25V
Crss	Reverse Transfer Capacitance		15			f=1.0MHz
Qg	Total Gate Charge		52			VDS=400V
Qgs	Gate- to- Source Charge		10		nC	ID=18A
Qgd	Gate-to-Drain(" Miller") Charge		19			VGS=10V

#### **Source-Drain Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
IS	Continuous Source Current			18	Α	Integral pn- diode
ISM	Maximum Pulsed Current			72	Α	in MOSFET
VSD	Diode Forward Voltage			1.4	V	IS=9A,VGS=0V
trr	Reverse Recovery Time		485		nS	VGS=0V
Qrr	Reverse Recovery Charge		4		μC	IS=18A,di/dt=100 A/μs

#### Notes:

<sup>\* 1.</sup> Repetitive rating, pulse width limited by maximum junction temperature.

<sup>\* 2.</sup> Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%



#### **Typical Feature Curve**

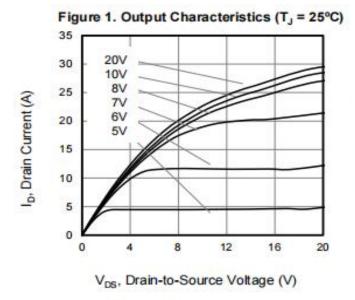


Figure 3. Drain Current vs. Temperature

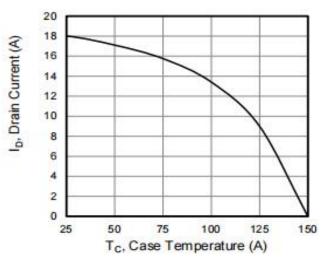
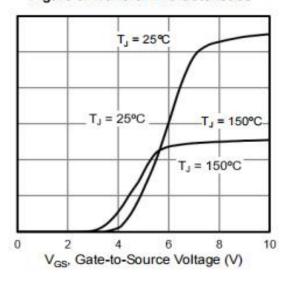


Figure 5. Transfer Characteristics



lp, Drain Current (A)

Figure 2. Body Diode Forward Voltage

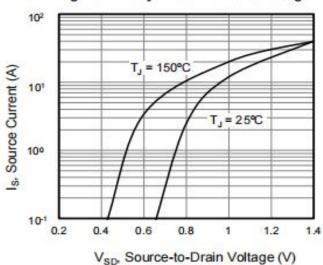


Figure 4. BV<sub>DSS</sub> Variation vs. Temperature

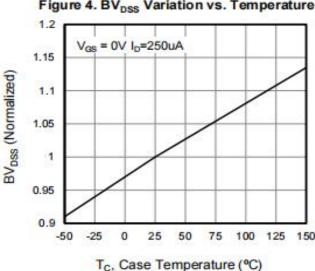


Figure 6. On-Resistance vs. Temperature

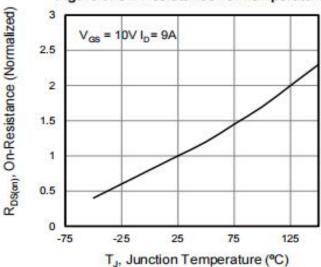
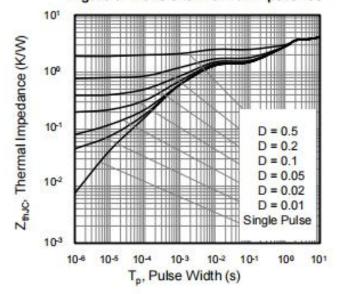




Figure 7. Capacitance Figure 8. Gate Charge 104 V<sub>DD</sub> = 100V Ves, Gate-to-Source Voltage (V) Ciss V<sub>DD</sub> = 250V 8 Capacitance (pF) 103  $V_{DD} = 400V$ Coss 6 102 4 Crss 101 V<sub>GS</sub> = 0V f = 1MHz 2 10° 0 0 10 20 30 40 50 0 10 20 30 60 40 V<sub>DS</sub>, Drain-to-Source Voltage (V) Q<sub>q</sub>, Total Gate Charge (nC)

Figure 9. Transient Thermal Impedance





## **Test Circuits and Waveforms**



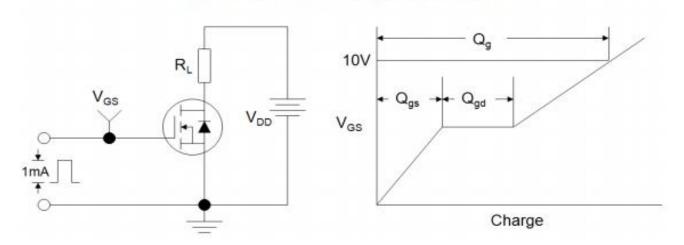


Figure B: Resistive Switching Test Circuit and Waveform

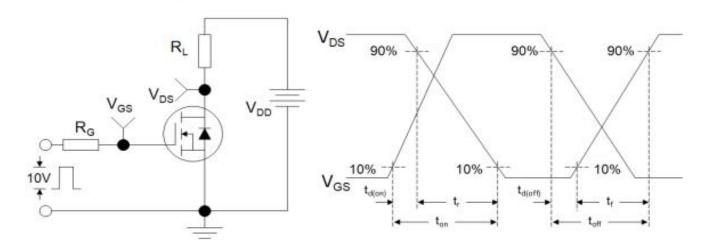
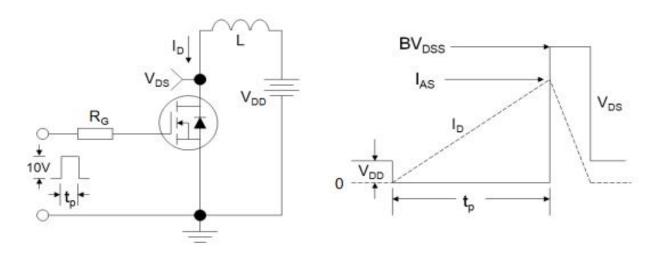
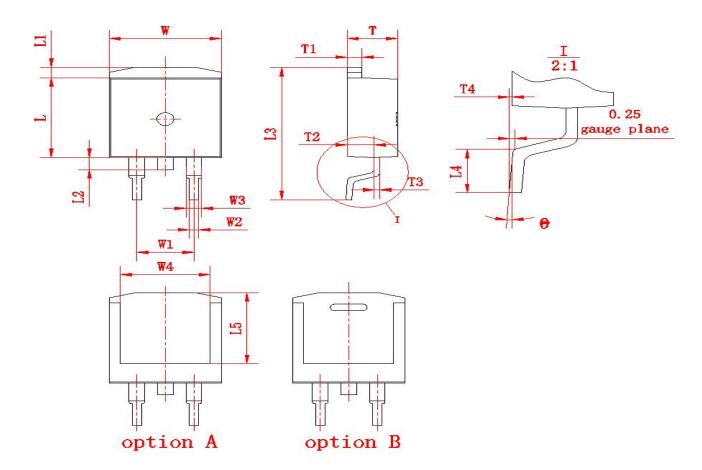


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





# Package outline drawing(TO-263 Unit: mm)



(单位: mm)

符号	尺寸		<b>₩</b> □	F	尺寸		尺寸	
付ち	Min	Max	符号	Min	Max	符号	Min	Max
W	9. 80	10. 20	L1	1.00	1.40	T1	1. 20	1.40
<b>W</b> 1	(5.	08)	L2	1. 20	1.60	T2	2. 20	2. 60
W2	0. 70	0. 95	L3	15. 00	15. 60	Т3	0. 45	0. 65
W3	1. 17	1. 62	L4	2. 20	2.80	T4	0	0. 25
<b>W</b> 4	(8)	. 0)	L5	(8. 2)		θ	0°	8°
L	9. 00	9. 40	T	4. 30	4. 70			



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